

March 2013

# FQP27P06 P-Channel QFET® MOSFET

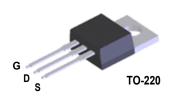
- 60 V, - 27 A, 70 m $\Omega$ 

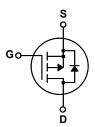
#### Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

#### **Features**

- - 27 A, 60 V,  $R_{DS(on)}$  = 70 m $\Omega$  (Max.) @  $V_{GS}$  = 10 V,  $I_D$  = 13.5 A
- Low Gate Charge (Typ. 33 nC)
- Low Crss (Typ. 120 pF)
- · 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating





### Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter			FQP27P06	Unit
V <sub>DSS</sub>	Drain-Source Voltage		-60	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		°C)	-27	Α
		- Continuous (T <sub>C</sub> = 10	0°C)	-19.1	Α
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	-108	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 25	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy		(Note 2)	560	mJ
I <sub>AR</sub>	Avalanche Current		(Note 1)	-27	А
E <sub>AR</sub>	Repetitive Avalanche Energy		(Note 1)	12	mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	-7.0	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)			120	W
	- Derate above 25°C			0.8	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to +175	°C
Tı	Maximum lead temperature for soldering purposes,			300	°C
· L	1/8" from case for 5 seconds			200	

### **Thermal Characteristics**

Symbol	Parameter	FQP27P06	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	1.25	°C/W	
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Typ.	0.5	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	°C/W	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	racteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-60			V
ΔBV <sub>DSS</sub> / ΔΤ <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 μA, Referenced to 25°C		-0.06		V/°C
I <sub>DSS</sub>	Zana Oaka Malkana Basin Oamank	V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V			-1	μА
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -48 V, T <sub>C</sub> = 150°C			-10	μА
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = -25 V, V <sub>DS</sub> = 0 V			-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = 25 V, V <sub>DS</sub> = 0 V			100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-2.0		-4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -13.5 A		0.055	0.07	Ω
g <sub>FS</sub>	Forward Transconductance V <sub>DS</sub> = -30 V, I <sub>D</sub> = -13.5 A			12.4		S
C <sub>iss</sub>	Input Capacitance Output Capacitance Payers Transfer Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		1100 510	1400 660	pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance			120	155	pF
	ng Characteristics	T	ı	I		
t <sub>d(on)</sub>	Turn-On Delay Time $V_{DD} = -30 \text{ V}, I_D = -13.5 \text{ A},$			18	45	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		185	380	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			30	70	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)		90	190	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = -48 \text{ V}, I_{D} = -27 \text{ A},$		33	43	nC
Q <sub>gs</sub>	Gate-Source Charge	163 11		6.8		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4)		18	-	nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				-27	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	Forward Current			-108	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -27 A			-4.0	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -27 A,		105		ns

Notes: 
1. Repetitive Rating : Pulse width limited by maximum junction temperature 
2. L = 0.9mH, I<sub>AS</sub> = -27A, V<sub>DD</sub> = -25V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C 
3. I<sub>SD</sub>  $\leq$  -27A, di/dt  $\leq$  300A/µs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 
4. Essentially independent of operating temperature

## **Typical Characteristics**

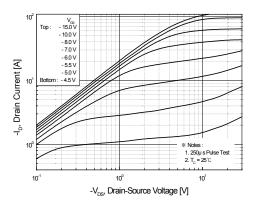


Figure 1. On-Region Characteristics

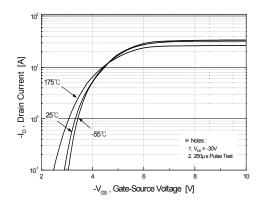


Figure 2. Transfer Characteristics

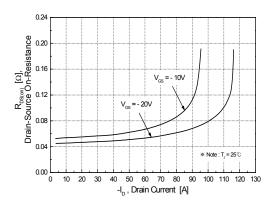


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

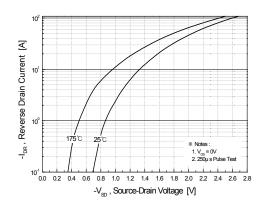


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

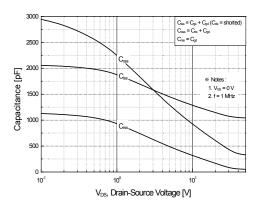


Figure 5. Capacitance Characteristics

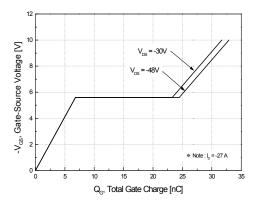
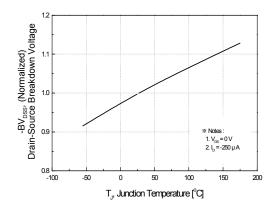


Figure 6. Gate Charge Characteristics

# Typical Characteristics (Continued)



25 (Normalized)

Normalized

Normalized

Normalized

Normalized

1.5 (Normalized)

Normalized

1.5 (Normalized)

1.5 (Normalized)

1.7 (Normalized)

1.8 (Normalized)

1.9 (Normalized)

1.9 (Normalized)

1.9 (Normalized)

1.0 (Normalized)

1.0 (Normalized)

1.1 (Normalized)

1.1 (Normalized)

1.2 (Normalized)

1.3 (Normalized)

1.4 (Normalized)

1.5 (Normalized)

1.5 (Normalized)

1.5 (Normalized)

1.5 (Normalized)

1.7 (Normalized)

1.8 (Normalized)

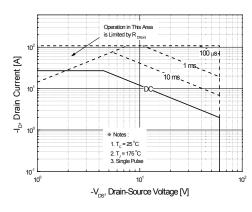
1.9 (Normalized)

1.9 (Normalized)

1.0 (No

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



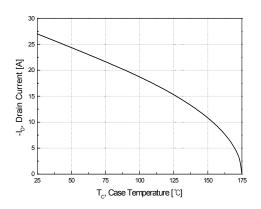


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

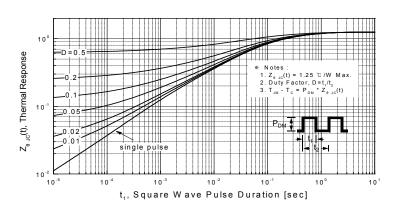
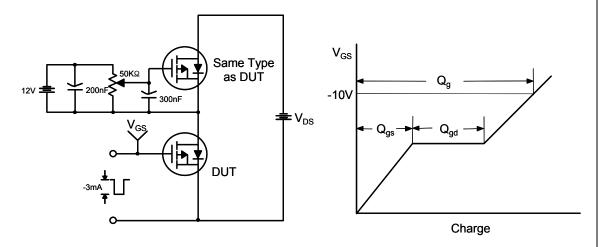
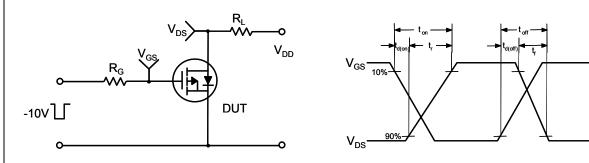


Figure 11. Transient Thermal Response Curve

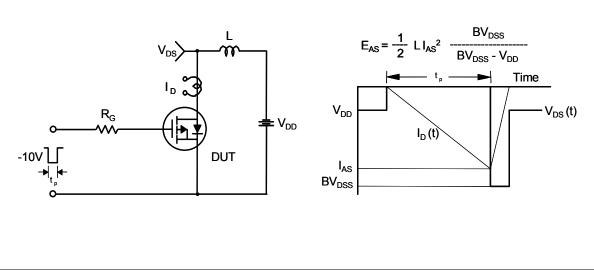
#### **Gate Charge Test Circuit & Waveform**



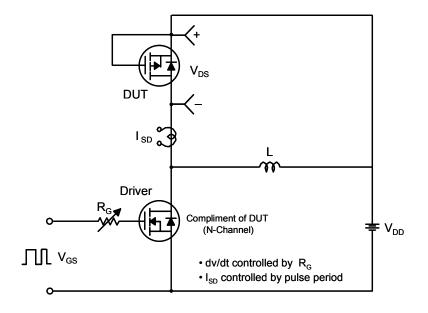
#### **Resistive Switching Test Circuit & Waveforms**

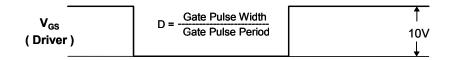


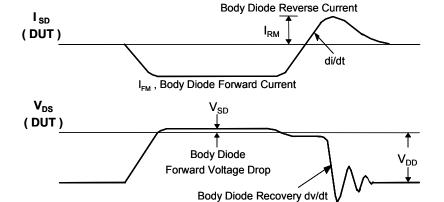
#### **Unclamped Inductive Switching Test Circuit & Waveforms**

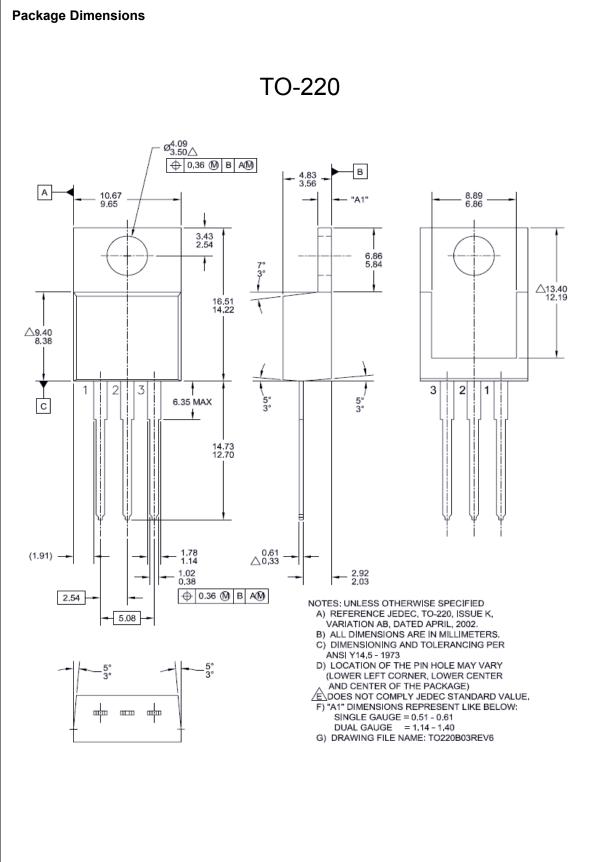


#### Peak Diode Recovery dv/dt Test Circuit & Waveforms













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